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	Application No.	Applicant(s)
Nation of Allowability	10/804,430	KIM ET AL.
Notice of Allowability	Examiner	Art Unit
	Lan Vinh	1765
The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this or other appropriate communica IGHTS. This application is subje	application. If not included ation will be mailed in due course. THIS
1.   This communication is responsive to Amendment filed on	<u>2/9/2006</u> .	
2. The allowed claim(s) is/are 1.4-21 and 24-39.		
<ul> <li>3.  Acknowledgment is made of a claim for foreign priority uner a)  All b)  Some* c)  None of the:</li> <li>1.  Certified copies of the priority documents have</li> <li>2.  Certified copies of the priority documents have</li> </ul>	e been received.	
3.  Copies of the certified copies of the priority documents have been received in this national stage application from the		
International Bureau (PCT Rule 17.2(a)).		
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		ply complying with the requirements
<ol> <li>A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give</li> </ol>	itted. Note the attached EXAMINes reason(s) why the oath or dec	IER'S AMENDMENT or NOTICE OF laration is deficient.
5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.		
(a) including changes required by the Notice of Draftspers	son's Patent Drawing Review ( P	TO-948) attached
1) 🗌 hereto or 2) 🗍 to Paper No./Mail Date		
<ul> <li>(b) ☐ including changes required by the attached Examiner's</li> <li>Paper No./Mail Date</li> </ul>	s Amendment / Comment or in the	ne Office action of
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t	.84(c)) should be written on the dr he header according to 37 CFR 1.1	awings in the front (not the back) of I21(d).
<ol> <li>DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT</li> </ol>	sit of BIOLOGICAL MATERIA FOR THE DEPOSIT OF BIOLOG	AL must be submitted. Note the GICAL MATERIAL.
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5. Notice of Inform	al Patent Application (PTO-152)
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. 🗌 Interview Summ	ary (PTO-413),
3. Information Disclosure Statements (PTO-1449 or PTO/SB/0	Paper No./Mail 08), 7. 🗌 Examiner's Ame	Date endment/Comment
Paper No./Mail Date <u>21306</u> 4. Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. ⊠ Examiner's State 9. □ Other	ement of Reasons for Allowance
		Lan Vinh AU 1765

Application/Control Number: 10/804,430

**Art Unit: 1765** 

## Allowable Subject Matter

1. Claims 1, 4-21, 24-39 allowed.

The following is an examiner's statement of reasons for allowance:

Regarding claims 1, 21, the cited prior art of record, taken alone or in combination, fails to disclose or suggest a method for etching a substrate comprises a step/limitation of alternatively etching said substrate with a first etchant and a second etchant, wherein said first etchant has a low selectivity to a first hard mask material of said first hard mask layer, a third hard mask material of said a third hard mask layer, and a first barrier layer material of said first barrier layer, but a high selectivity to a second hard mask material of said second hard mask layer, wherein said alternately etching includes etching partially through said low-k layer and said first barrier layer with said second etchant, in combination with the rest of the limitations of claims 1, 21. The closest cited prior art of Soda et al (US 2003/0190907) discloses a method for manufacturing semiconductor device comprises a step of etching partially through a low-k layer 20 with C4F8 gas /second etchant without etching a first barrier layer 19 ( col 3, paragraph 0045; fig. 6A-6B)

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Application/Control Number: 10/804,430

Art Unit: 1765

## Conclusion

Page 3

2. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Lan Vinh whose telephone number is 571 272 1471. The examiner can normally be reached on M-F 8:30-5:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nadine Norton can be reached on 571 272 1465. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

March 3, 2006